

Title (en)
Pellicle for lithography

Title (de)
Schutzmembrane für Lithographie

Title (fr)
Pellicule pour lithographie

Publication
EP 1843201 A1 20071010 (EN)

Application
EP 07005629 A 20070319

Priority
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Abstract (en)
The invention provides a pellicle for lithography used in the photolithography, affording a wider range of transmissivity to inclined incident beams that can be used in a photolithographic procedure. The pellicle used in the photolithography using ArF excimer laser beams is characterized in that the pellicle has a pellicle membrane having a thickness which is 400 nm or smaller and at which the membrane exhibits a local maximum transmissivity to a vertically incident ArF excimer laser beam. Also, the pellicle is characterized by having a pellicle membrane having a thickness at which the membrane exhibits a local maximum transmissivity to an inclined incident ArF excimer laser beam. Herein, the angle of inclined incidence is preferably 13.4 degrees, and the pellicle membrane has preferably a thickness of 600 nm or smaller, in particular in a range selected from 560 to 563 nm and 489 to 494 nm and 418 to 425 nm and 346 to 355 nm and 275 to 286 nm and 204 to 217 nm.

IPC 8 full level
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CPC (source: EP KR US)
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Citation (search report)
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